Physics of Electronics: 7. Junction Diodes

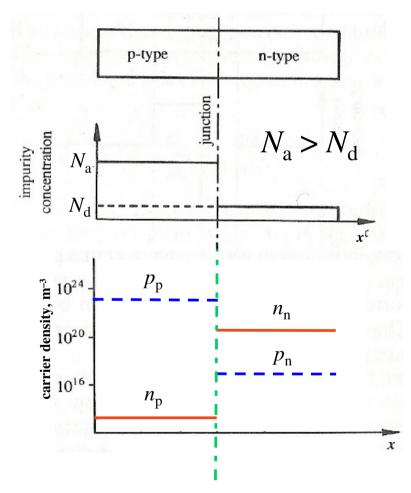
July – December 2008

Contents overview

- Pn junction in equilibrium.
- Current flow in a pn junction with forward bias.
- Current flow in a pn junction with reversed bias.
- IV charachteristics of a junction diode
- Electron and hole efficiencies.
- Pn junction with finite dimensions.
- Depletion-layer capacitance

Pn junction in equilibrium

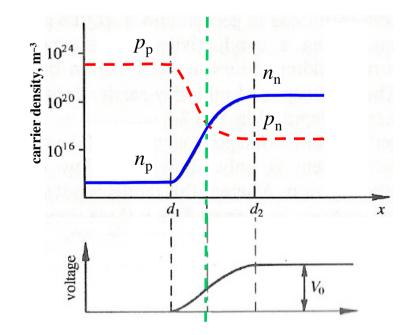
• Consider a pn junction with abrupt transition



Initially, the density of carriers change abruptly at the junction.

This change of concentration causes diffusion which is stopped by exposition of ionized impurities at the depletion layer.

In equilibrium, a voltage difference is created across the depletion layer.



Pn junction in equilibrium

- Voltage across the depletion layer
 - Start with continuity eq. for holes

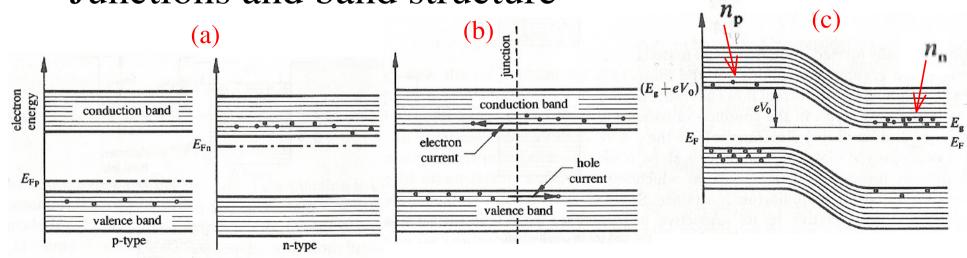
$$\frac{\partial(\delta p)}{\partial t} = -\frac{\delta p}{\tau_{\rm Lh}} + \mu_{\rm h} \mathscr{E}_x \frac{\partial(\delta p)}{\partial x} + D_{\rm h} \frac{\partial^2(\delta p)}{\partial x^2}$$

$$D_{\rm h}/\mu_{\rm h} = kT/e$$

& integrating

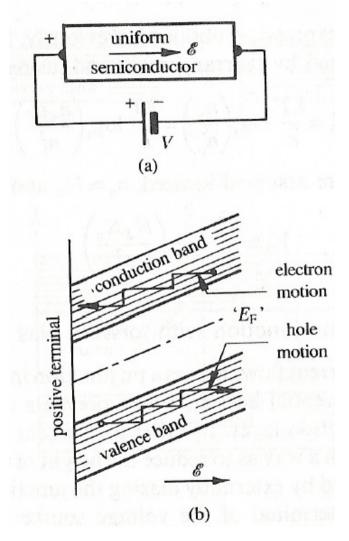
$$p_{\rm p} = p_{\rm n} \exp(eV_0/kT)$$

• Junctions and band structure



 $n_{\rm n}/n_{\rm p} = \exp(eV_0/kT)$

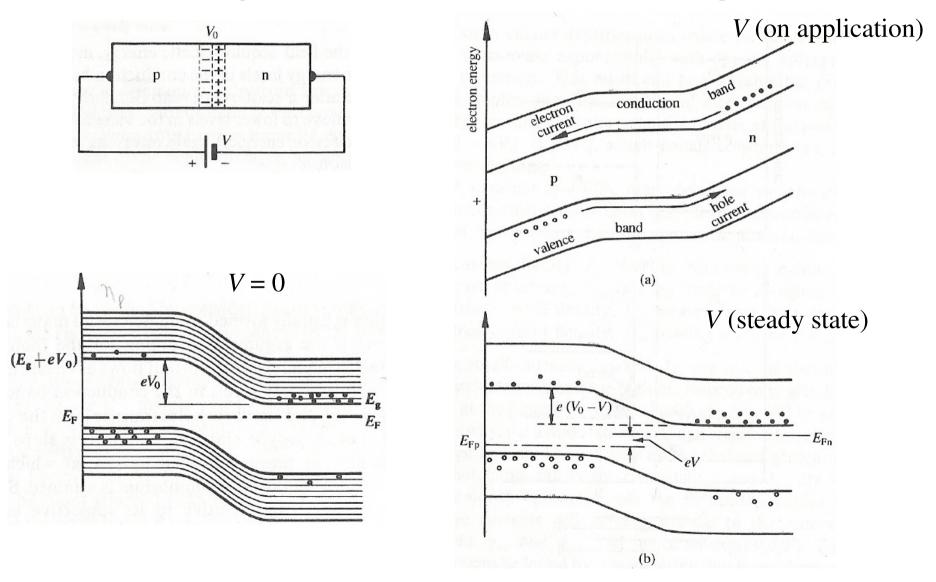
• Consider a uniform sC biased with a voltage V:



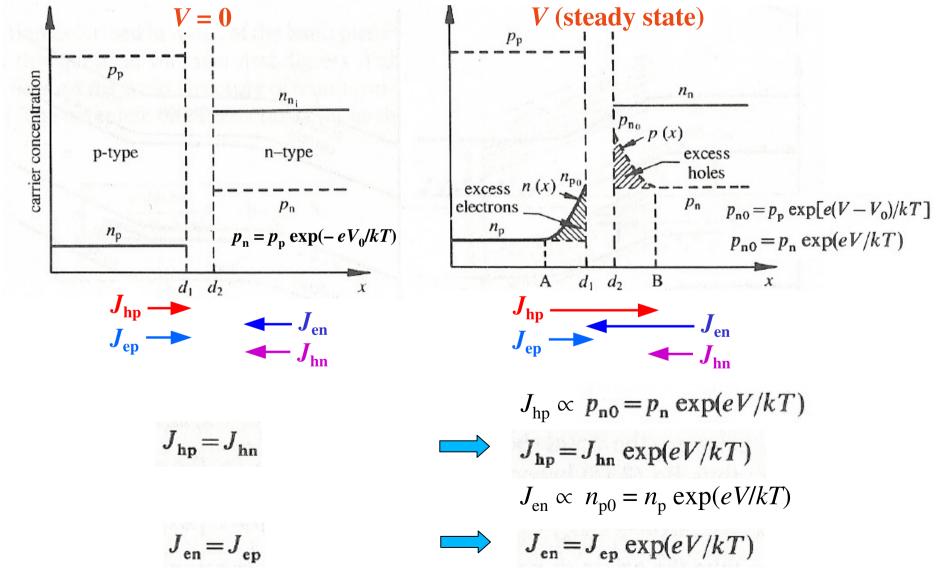
The whole band structure tilts (one end of the sC has more energy than the other).

Electrons and holes move in the field (in opposite directions.

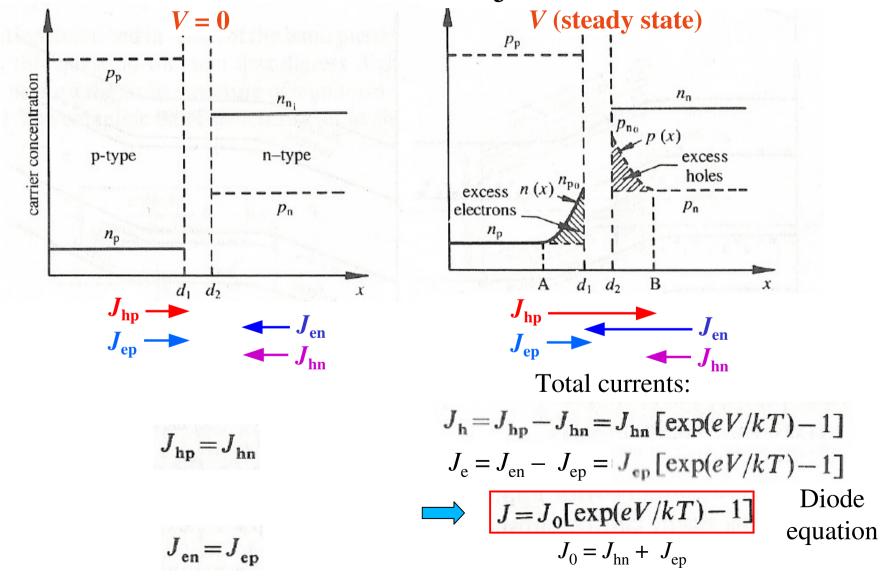
• Consider a junction biased with a voltage V:



• Excess carriers in a biased junctions:



• Excess carriers in a biased junctions:

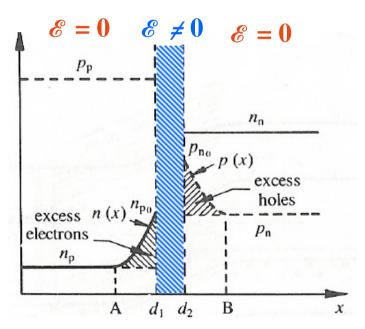


- Diode equation:
- Continuity eq. for h^+ at $x \ge d_2$ V (steady state) $\frac{\partial(\delta p)}{\partial t} = -\frac{\delta p}{\tau_{\rm Lh}} + \mu_{\rm h} \mathscr{E}_{x} \frac{\partial(\delta p)}{\partial x} + D_{\rm h} \frac{\partial^{2}(\delta p)}{\partial x^{2}}$ $\mathscr{E} = \mathbf{0} \quad \mathscr{E} \neq \mathbf{0} \quad \mathscr{E} = \mathbf{0}$ $p_{\rm p}$ $\frac{\mathrm{d}^2(\delta p)}{\mathrm{d}x^2} = \frac{\delta p}{\tau_{\mathrm{L}h} D_h} = \frac{\delta p}{L_h^2}$ nn p_{no} p(x) $\delta p = C_1 \exp(-x/L_h) + C_2 \exp(+x/L_h)$ excess holes excess $n(x) \frac{n_{p_0}}{x}$ But $\delta p = p(x) - p_n \rightarrow 0$ when $x \rightarrow \infty$, then $C_2 = 0$ p_n electrons and changing origin to $x = d_2$ where $p(x) = p_{n0}$: np $p(x) = (p_{n0} - p_n) \exp(-x/L_h) + p_n$ $d_1 d_2$ A В • Since $\mathscr{E} = 0$, there is only diffusion:

 $J_{\rm Dh} = -eD_{\rm h}dp/dx \qquad \qquad J_{\rm h} = -eD_{\rm h}[-(1/L_{\rm h}) (p_{\rm n0} - p_{\rm n}) \exp(-x/L_{\rm h})]$ $x = 0 \qquad \qquad J_{\rm h}|_{d_2} = (eD_{\rm h}/L_{\rm h}) (p_{\rm n0} - p_{\rm n}) \qquad \qquad P_{\rm n0} = p_{\rm n} \exp(eV/kT) \qquad \qquad J_{\rm h}|_{d_2} = (eD_{\rm h}/L_{\rm h})p_{\rm n} \left[\exp(eV/kT) - 1\right]$

- Diode equation:
 - Continuity eq. for e^- at $x \le d_1$:

V (steady state)



$$J_{e|_{d_1}} = (eD_e n_p/L_e) [exp(eV/kT) - 1]$$

Total current is then:

$$J = J_{h} + J_{e} = e \left(\frac{D_{h}p_{n}}{L_{h}} + \frac{D_{e}n_{p}}{L_{e}} \right) \left[\exp(eV/kT) - 1 \right]$$

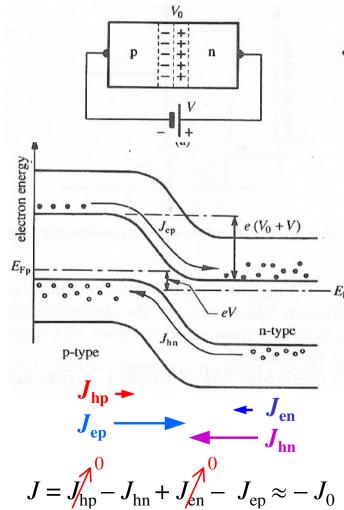
$$J_{0}$$

For $V \gg kT$:

 $J \simeq J_0 \exp(eV/kT)$

Pn junction with reversed bias

- Currents through the junction :
 - Applying diode equation (with -V):

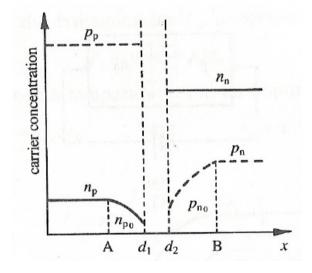


$$J = J_0 [\exp(-eV/kT) - 1] = -J_0 [1 - \exp(-eV/kT)]$$

For V >> kT: $J \approx -J_0$

Pn junction with reversed bias

- Minority carriers:
 - As before (with -V):



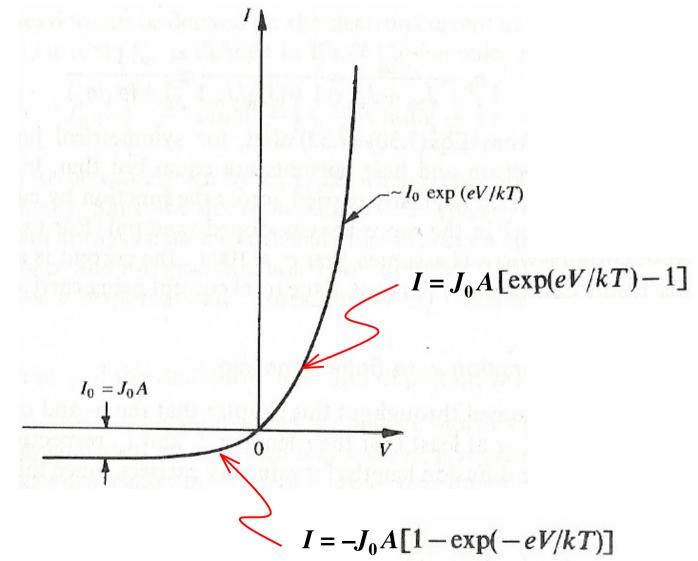
 $n_{p0} = n_p \exp(-eV/kT)$ $p_{n0} = p_n \exp(-eV/kT)$

- Applying continuity eq. as before

 $p(x) = p_{\rm n} \{ [\exp(-eV/kT) - 1] \exp(-x/L_{\rm h}) + 1 \}$

I-V curve of a junction diode

• Applying the results for the current density:



Electron-holes efficiencies

- Relative hole and electron currents:
 - Excess carriers:

$$J_{h} = J_{hp} - J_{hn} = J_{hn} [exp(eV/kT) - 1]$$

$$J_{e} = J_{en} - J_{ep} = J_{ep} [exp(eV/kT) - 1]$$

$$J_{e} = J_{en} - J_{ep} = J_{ep} [exp(eV/kT) - 1]$$

- Continuity equations:

$$\begin{array}{c} J_{\rm h}|_{d_2} = (eD_{\rm h}/L_{\rm h})p_{\rm n} \left[\exp(eV/kT) - 1 \right] \\ J_{\rm e}|_{d_1} = (eD_{\rm e}n_{\rm p}/L_{\rm e}) \left[\exp(eV/kT) - 1 \right] \end{array} \qquad \begin{array}{c} J_{\rm h} \\ J_{\rm e} = \frac{J_{\rm hn}}{J_{\rm ep}} = \frac{J_{\rm hn}}{L_{\rm h}N_{\rm d}} \frac{L_{\rm e}N_{\rm a}}{D_{\rm e}} \end{array}$$

- Einstein $(D_e/\mu_e = D_h/\mu_h = kT/e)$ and conductivity $(\sigma = e(n\mu_e + p\mu_h))$ eqs.:

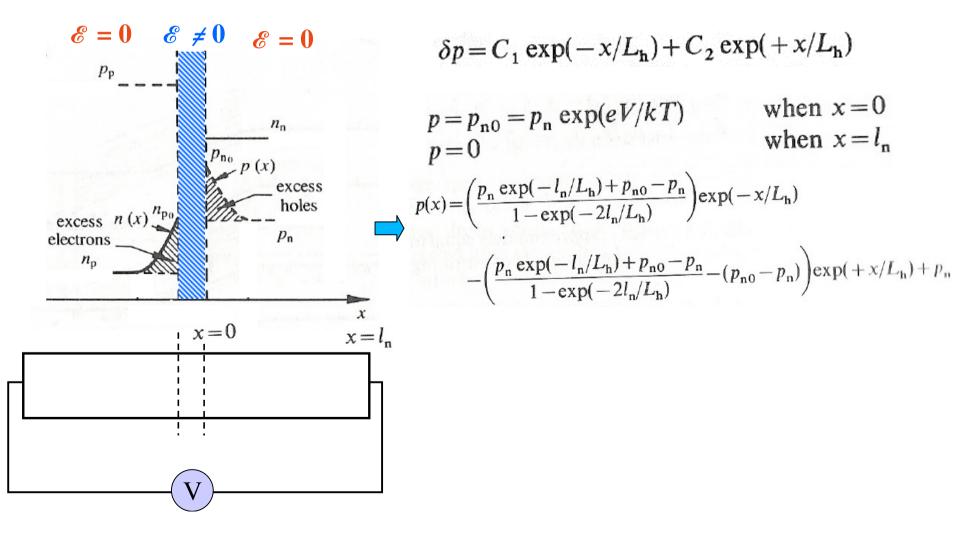
$$\frac{J_{\rm h}}{J_{\rm e}} = \frac{L_{\rm e}}{L_{\rm h}} \frac{\mu_{\rm h} N_{\rm a}}{\mu_{\rm e} N_{\rm d}} \qquad \Longrightarrow \qquad J_{\rm h} / J_{\rm e} \simeq \sigma_{\rm p} / \sigma_{\rm n}$$

– Hole efficiency:

$$\eta_{\rm h} \equiv \frac{J_{\rm hn}}{J_{\rm hn} + J_{\rm ep}} = \frac{1}{1 + (J_{\rm ep}/J_{\rm hn})} \simeq \frac{1}{1 + (\sigma_{\rm n}/\sigma_{\rm p})} \qquad \eta_{\rm h} \equiv \frac{J_{\rm ep}}{J_{\rm hn} + J_{\rm ep}} = \frac{1}{1 + (J_{\rm hn}/J_{\rm ep})} \simeq \frac{1}{1 + (\sigma_{\rm p}/\sigma_{\rm n})}$$

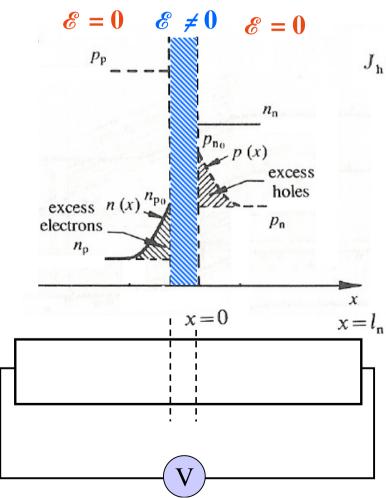
Pn junction with finite dimensions

- Current in a finite junction:
 - From the continuity eq. we obtained



Pn junction with finite dimensions

- Current in a finite junction:
 - Currents:



For holes:

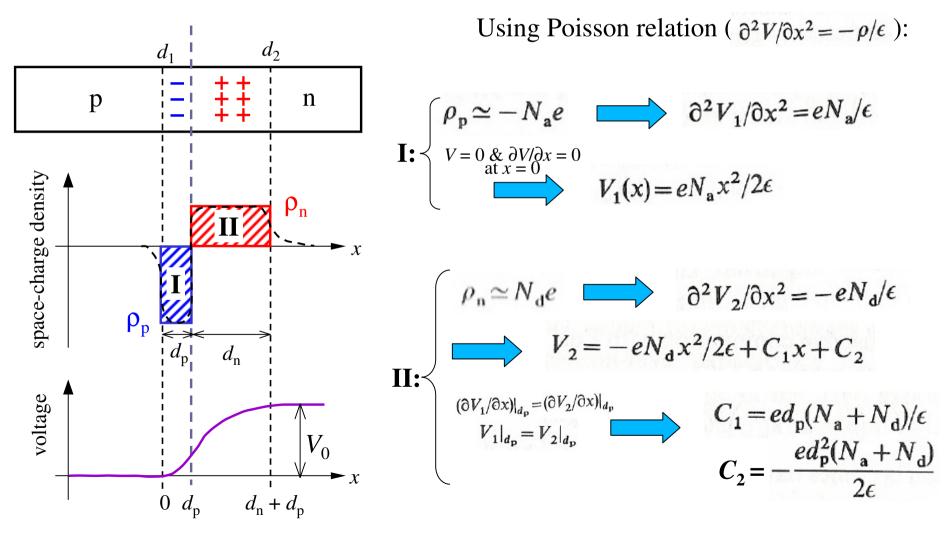
$$J_{\mathbf{h}} = -eD_{\mathbf{h}}\left(\frac{\mathrm{d}p(x)}{\mathrm{d}x}\right)\Big|_{x=0} = \frac{eD_{\mathbf{h}}}{L_{\mathbf{h}}}p_{\mathbf{n}} \tanh\left(\frac{l_{\mathbf{n}}}{L_{\mathbf{h}}}\right)\left[\exp(eV/kT) - 1\right]$$

Idem for the electrons. Therefore the saturation current is:

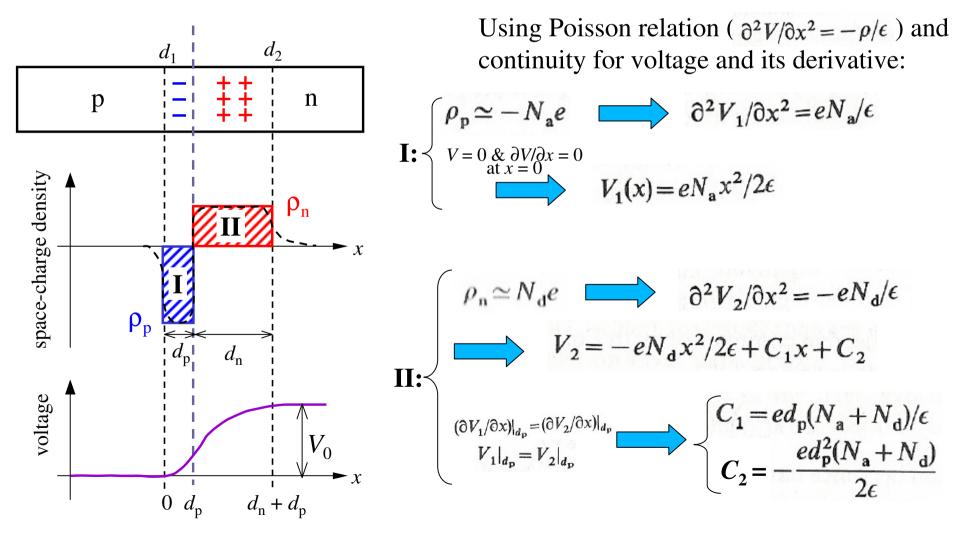
$$J_0 = e \left[\frac{D_h p_n}{L_h} \tanh\left(\frac{l_n}{L_h}\right) + \frac{D_e n_p}{L_e} \tanh\left(\frac{l_p}{L_e}\right) \right]$$

 $\rightarrow 0$ when $l \gg L$ (L ~ 1 mm)

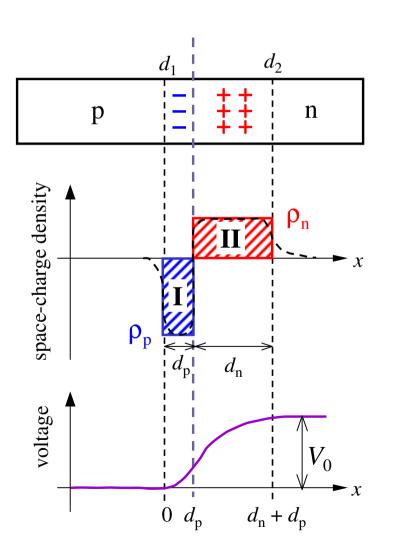
• The depletion layer forms a capacitance (important for high frequency applications)



• The depletion layer forms a capacitance (important for high frequency applications)



• Expressions for the depletion layer:



Applying
$$\mathscr{E} = 0$$
 at $x \ge d_n + d_p$:
 $(\partial V_2 / \partial x)|_{d_n + d_p} = 0$
 $d_p / d_n = N_d / N_a$

Applying $V = V_0$ at $x \ge d_n + d_p$ & using previous relation:

This expressions are still applicable for a biased junction $V_0 \leftrightarrow V_0 - V$

- Capacitance of the depletion layer:
 - Charge per unit area accumulated at the depletion layer

$$Q_{j} = eN_{d}d_{n} = eN_{a}d_{p}$$
 $Q_{j} = \left(\frac{2\epsilon eV_{j}N_{a}N_{d}}{N_{a} + N_{d}}\right)^{1/2}$

– The capacitance per unit area $(C_j = dQ_j/dV_j)$ is then:

